

NO-A191 248

THIN FILM RESEARCH DIAGNOSTICS INSTRUMENTATION(U) NEW
MEXICO UNIV ALBUQUERQUE MCNEIL 21 OCT 87
AFOSR-TR-87-1757 AFOSR-85-0091

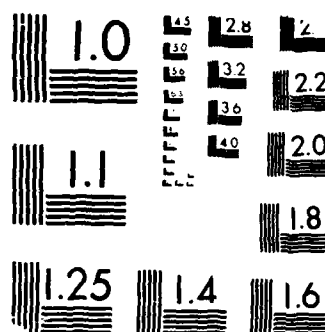
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MICROCOPY RESOLUTION TEST CHART
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REPORT DOCUMENTATION PAGE

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FINAL REPORT FOR AFOSR CONTRACT #85-0091

Equipment purchased under this contract in support of thin film research includes the following:

Ellipsometer package	\$ 27,000
Ar-ion laser package	28,000
Nomarski Microscope	15,801
Excimer laser package	50,000
TOTAL	\$120,801
 UNM Matching	 \$ 26,133
 AFOSR Portion	 \$ 94,668

All the equipment has been used in the Thin Film Laboratory for deposition and analysis of thin films. In particular, the Ar-ion laser is being used to investigate film scatter at multiple wavelengths. The excimer laser is being used to enhance deposition mechanisms; it illuminates a coated surface throughout film deposition. The microscope and ellipsometer are part of diagnostics used to analyze films.

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